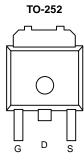


N-Channel 40-V (D-S) MOSFET

PRODUCT SUMMARY						
V _{DS} (V)	R _{DS(on)} (Ω)	I _D (A) ^{a, e}	Q _g (Typ)			
40	0.013 at V_{GS} = 10 V	55	42 nC			
40	0.018 at V_{GS} = 4.5 V	45	42 110			



Top View

FEATURES

- TrenchFET[®] Power MOSFET
- •
- 100 % R_g and UIS Tested Compliant to RoHS Directive 2011/65/EU •

APPLICATIONS

- OR-ing
- Server
 - DC/DC G



N-Channel MOSFET

D

C

ABSOLUTE MAXIMUM RATINGS	(T _A = 25 °C, unle	ess otherwise n	oted)	
Parameter	Symbol	Limit	Unit	
Drain-Source Voltage	V _{DS}	40	V	
Gate-Source Voltage		V _{GS}	± 20	V
	T _C = 25 °C		55 ^{a, e}	
Continuous Drain Current ($T_1 = 175 \ ^{\circ}C$)	T _C = 70 °C		45 ^e	
	T _A = 25 °C	I _D	15.8 ^{b, c}	A
	T _A = 70 °C		12 ^{b, c}	
Pulsed Drain Current	I _{DM}	200	7	
Avalanche Current Pulse	L = 0.1 mH		39	
Single Pulse Avalanche Energy	L = 0.1 MH	E _{AS}	94.8	mJ
Continuous Source-Drain Diode Current	T _C = 25 °C	la la	90 ^{a, e}	Α
Continuous Source-Drain Diode Current	T _A = 25 °C	I _S	3.13 ^{b, c}	A
	T _C = 25 °C		100 ^a	
Movimum Dower Discinction	T _C = 70 °C	PD	75	w
Maximum Power Dissipation	$T_{A} = 25 \text{ °C}$		3.75 ^{b, c}	vv
	T _A = 70 °C		2.63 ^{b, c}	
Operating Junction and Storage Temperature Ra	T _J , T _{stg}	- 55 to 175	°C	

THERMAL RESISTANCE RATINGS						
Parameter		Symbol	Тур.	Max.	Unit	
Maximum Junction-to-Ambient ^{b, d}	$t \le 10 \text{ sec}$	R _{thJA}	32	40	°C/W	
Maximum Junction-to-Case	Steady State	R _{thJC}	0.5	0.6	0/11	

Notes:

a. Based on $T_C = 25 \text{ °C}$. b. Surface mounted on 1" x 1" FR4 board.

a. t = 10 sec.
d. Maximum under steady state conditions is 90 °C/W.
e. Calculated based on maximum junction temperature. Package limitation current is 90 A.

NTD5806NT4G

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Parameter	Symbol	Test Conditions	Min.	Тур.	Max.	Unit
Static						•
Drain-Source Breakdown Voltage	V _{DS}	$V_{GS} = 0 \text{ V}, \text{ I}_{D} = 250 \mu\text{A}$ 40				V
V _{DS} Temperature Coefficient	$\Delta V_{DS}/T_{J}$	I _D = 250 μA		35		mV/°C
V _{GS(th)} Temperature Coefficient	$\Delta V_{GS(th)}/T_J$	iβ = 200 μΛ		- 7.5		mv/ C
Gate-Source Threshold Voltage	V _{GS(th)}	$V_{DS} = V_{GS}, I_D = 250 \ \mu A$	1.5		2.5	V
Gate-Source Leakage	I _{GSS}	V_{DS} = 0 V, V_{GS} = ± 20 V			± 100	nA
Zero Gate Voltage Drain Current	I _{DSS}	$V_{DS} = 40 V, V_{GS} = 0 V$			1	μA
Zero Gale vollage Drain Current		V_{DS} = 40 V, V_{GS} = 0 V, T_{J} = 55 °C			10	
On-State Drain Current ^a	I _{D(on)}	$V_{DS} \ge 5 \text{ V}, V_{GS} = 10 \text{ V}$	90			Α
		V _{GS} = 10 V, I _D = 38.8 A		0.012		Ω
Drain-Source On-State Resistance ^a	R _{DS(on)}	$V_{GS} = 4.5 \text{ V}, \text{ I}_{D} = 37 \text{ A}$		0.014		
Forward Transconductance ^a	9 _{fs}	V _{DS} = 15 V, I _D = 38.8 A		160		S
Dynamic ^b						
Input Capacitance	C _{iss}			1801		pF
Output Capacitance	C _{oss}	$V_{DS} = 15 \text{ V}, \text{ V}_{GS} = 0 \text{ V}, \text{ f} = 1 \text{ MHz}$		725		
Reverse Transfer Capacitance	C _{rss}			570		
Total Gate Charge	Qg VD	V_{DS} = 15 V, V_{GS} = 10 V, I_{D} = 38.8 A		85	120	nC
				42	62	
Gate-Source Charge	Q _{gs}	V_{DS} = 15 V, V_{GS} = 4.5 V, I_{D} = 28.8 A		17		
Gate-Drain Charge	Q _{gd}			14		
Gate Resistance	R _g	f = 1 MHz		1.4	2.1	Ω
Turn-On Delay Time	t _{d(on)}			10	20	
Rise Time	t _r	V_{DD} = 15 V, R_L = 0.625 Ω		11	17]
Turn-Off Delay Time	t _{d(off)}	$I_D \cong$ 24 A, V_{GEN} = 10 V, R_g = 1 Ω		35	55	
Fall Time	t _f			10	15	
Turn-On Delay Time	t _{d(on)}			25	43	ns
Rise Time	t _r	V_{DD} = 15 V, R_L = 0.67 Ω		80	150	-
Turn-Off Delay Time	t _{d(off)}	$\text{I}_\text{D}\cong\text{22.5}$ A, V_GEN = 4.5 V, R_g = 1 Ω		26	42	
Fall Time	t _f			12	18	
Drain-Source Body Diode Characteristics	; ;					
Continuous Source-Drain Diode Current	ا _S	T _C = 25 °C			120	^
Pulse Diode Forward Current ^a	I _{SM}				120	A
Body Diode Voltage	V _{SD}	I _S = 22 A		0.8	1.2	V
Body Diode Reverse Recovery Time	t _{rr}			52	78	ns
Body Diode Reverse Recovery Charge	Q _{rr}	I _F = 20 A, di/dt = 100 A/μs, T _{.I} = 25 °C		70.2	105	nC
Reverse Recovery Fall Time	t _a	$r_F = 20 \text{ A}, \text{ al/al} = 100 \text{ A/}\mu\text{s}, \text{I}_{\text{J}} = 25 \text{ °C}$		27		
Reverse Recovery Rise Time	t _b			25		ns

Notes:

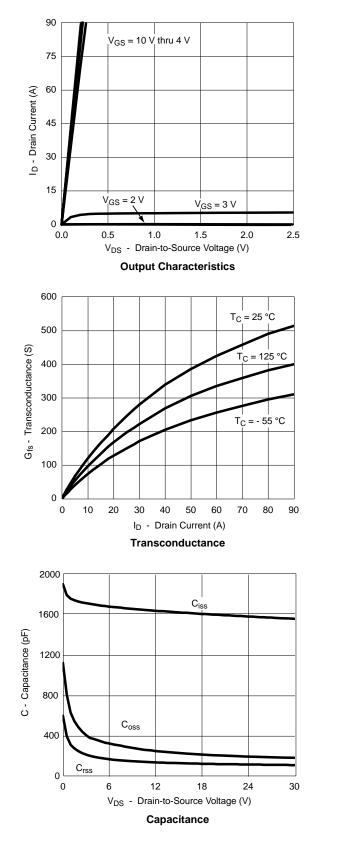
a. Pulse test; pulse width \leq 300 $\mu s,$ duty cycle \leq 2 %.

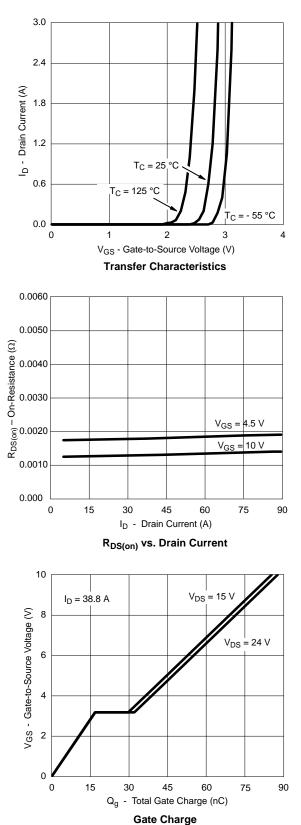
b. Guaranteed by design, not subject to production testing.

Stresses beyond those listed under "Absolute Maximum Ratings" may cause permanent damage to the device. These are stress ratings only, and functional operation of the device at these or any other conditions beyond those indicated in the operational sections of the specifications is not implied. Exposure to absolute maximum rating conditions for extended periods may affect device reliability.



TYPICAL CHARACTERISTICS (25 °C, unless otherwise noted)





0.001

0.000

0

2

4

6

V_{GS} - Gate-to-Source Voltage (V)

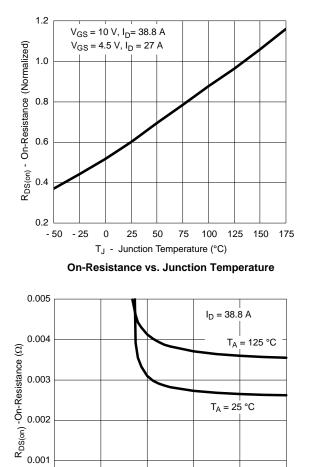
 $R_{DS(on)}$ vs. V_{GS} vs. Temperature

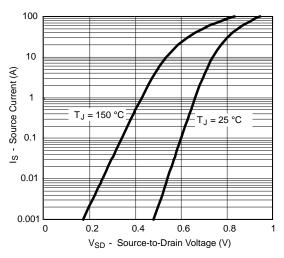
8

10

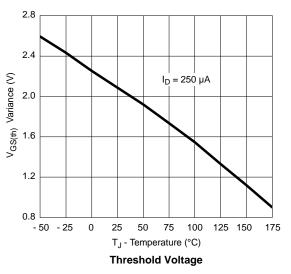


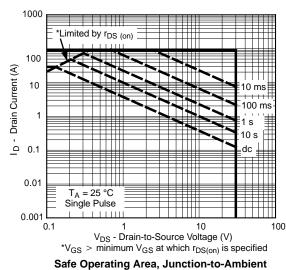
TYPICAL CHARACTERISTICS (25 °C, unless otherwise noted)

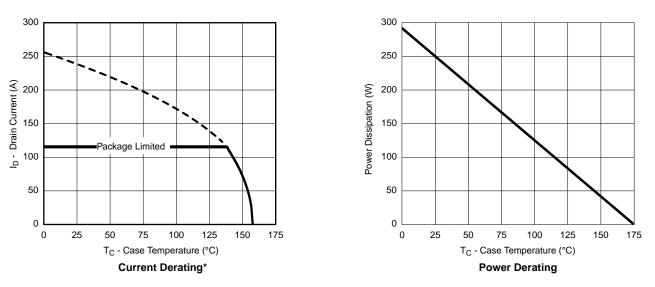




Forward Diode Voltage vs. Temperature

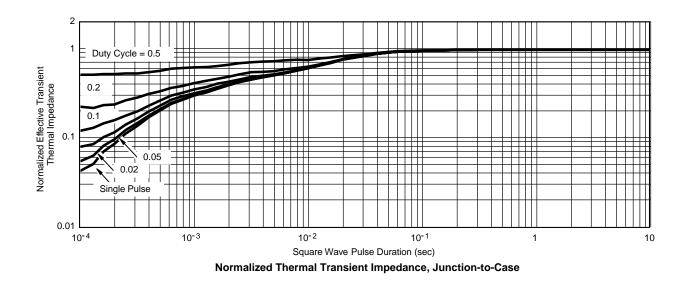






TYPICAL CHARACTERISTICS (25 °C, unless otherwise noted)

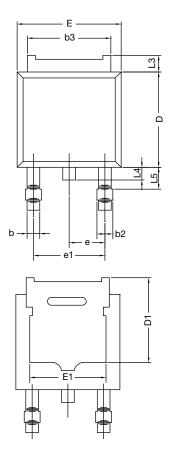
*The power dissipation P_D is based on $T_{J(max)} = 175$ °C, using junction-to-case thermal resistance, and is more useful in settling the upper dissipation limit for cases where additional heatsinking is used. It is used to determine the current rating, when this rating falls below the package limit.

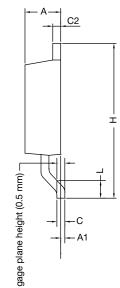


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TO-252AA CASE OUTLINE





	MILLIN	IETERS	INCHES			
DIM.	MIN.	MAX.	MIN.	MAX.		
А	2.18	2.38	0.086	0.094		
A1	-	0.127	-	0.005		
b	0.64	0.88	0.025	0.035		
b2	0.76	1.14	0.030	0.045		
b3	4.95	5.46	0.195	0.215		
С	0.46	0.61	0.018	0.024		
C2	0.46	0.89	0.018	0.035		
D	5.97	6.22	0.235	0.245		
D1	5.21	-	0.205	-		
Е	6.35	6.73	0.250	0.265		
E1	4.32	-	0.170	-		
Н	9.40	10.41	0.370	0.410		
е	2.28	BSC 0.090 BS		BSC		
e1	4.56	4.56 BSC		0.180 BSC		
L	1.40	1.78	0.055	0.070		
L3	0.89	1.27	0.035	0.050		
L4	-	1.02	-	0.040		
L5	1.14	1.52	0.045	0.060		
ECN: X12-0247-Rev. M, 24-Dec-12 DWG: 5347						

Note

• Dimension L3 is for reference only.



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